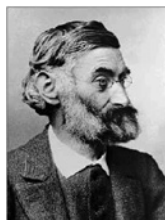


- Microwave Frequency Comb from a Semiconductor in a Scanning Tunneling Microscope
Mark J. Hagmann, Dmitry A. Yarotski, and Marwan S. Mousa
- Laser-assisted atom probe tomography of deformed minerals: a zircon case study
Alexandre La Fontaine, Sandra Piazzolo, Patrick Trimby, Limei Yang, and Julie Cairney
- Effect of Cu on nanoscale precipitation evolution and mechanical properties of a Fe-NiAl alloy
Qin Shen, Hao Chen, and Wenqing Liu
- Electron beam induced deposition for atom probe tomography specimen capping layers
David Diercks, Brian Gorman, and Hans Mulders
- Evaluation of analysis conditions for laser-pulsed atom probe tomography: example of cemented tungsten carbide
Baptiste Gault, Zirong Peng, Pyuck-Pa Choi, and Dierk Raabe
- Nano-scale stoichiometry analysis of a high temperature superconductor by atom probe tomography
Stella Pedrazzini, Andrew London, Baptiste Gault, David Saxey, Susannah Speller, Chris Grovenor, Mohsen Danaie, Michael Moody, Philip Edmondson, and Paul Bagot
- Additions of Dy, Nb and Ga on microstructure and magnetic properties of Nd₂Fe₁₄B/a-Fe nanocomposite permanent magnetic alloys
Xiaohua Tan, Kezhi Ren, Heyun Li, Hui Xu, and Ke Han
- Reflections on the projection of ions in atom probe tomography
Baptiste Gault and Frederic de Geuser
- Toward the Atomic-Level Mass Analysis of Biomolecules by the Scanning Atom Probe
Osamu Nishikawa and Masahiro Taniguchi
- Correlating atom probe tomography with atomic resolved scanning transmission electron microscopy: example of segregation at silicon grain boundaries
Andreas Stoffers, Juri Barthel, Christian Liebscher, Baptiste Gault, Oana Cojocaru-Mirédin, Christina Scheu, and Dierk Raabe
- Understanding of capping effects on the tip shape evolution and on the atom probe data of bulk LaAlO₃ using transmission electron microscopy
Jaebok Seol, Chang-Min Kwak, Young-Tae Kim, and Chan-Gyung Park
- Optimizing Atom Probe analysis with synchronous laser pulsing and voltage pulsing
L. Zhao, A. Normand, J. Houard, I. Blum, F. Delaroche, O. Latry, B. Ravelo, and F. Vurpillot
- New atom probe tomography reconstruction algorithm for multilayered samples: beyond the hemispherical constraint
Nicolas Rolland, Francois Vurpillot, Sebastien Duguay, and Didier Blavette
- Atom probe tomography characterization of nanoscale Cu-rich precipitates in 17-4 precipitate hardened stainless steel tempered at different temperatures
Zemin Wang, Xulei Fang, Hui Li, and Wenqing Liu
- Interface Segregation and Nitrogen Measurement in Fe-Mn-N Steel by Atom Probe Tomography
Brian Langelier, Hugo Van Landeghem, Gianluigi Botton, and Hatem Zurob
- On the analysis of clustering in an irradiated low alloy reactor pressure vessel steel weld
Kristina Lindgren, Krystyna Stiller, Pål Efsing, and Mattias Thuvander
- Core-shell structure of intermediate precipitates in a Nb-based Z-phase strengthened 12% Cr steel
Masoud Rashidi, Hans-Olof Andrén, and Fang Liu
- Single-Ion Deconvolution of Mass-Peak Overlaps for Atom Probe Microscopy
Andrew London, Daniel Haley, and Michael Moody
- Interfaces in oxides formed on NiAlCr doped with Y, Hf, Ti and B
Torben Boll, Krystyna Stiller, Bruce Pint, and Kinga Unocic
- Correlating Atom Probe Crystallography Measurements with Transmission Kikuchi Diffraction Data
A.J. Breen, K. Babinsky, A.C. Day, K. Eder, C.J. Oakman, P.W. Trimby, S. Primig, J.M. Cairney, and S.P. Ringer
- Analysis of Radiation Damage in Light Water Reactors: Comparison of Cluster Analysis Methods for the Analysis of Atom Probe Data
Paul Styman, Jonathan Hyde, Gérald Da Costa, Constantinos Hatzoglou, Hannah Weekes, Bertrand Radigue, Francois Vurpillot, Cristelle Pareige, Auriane Etienne, Giovanni Bonny, Nicolas Castin, Lorenzo Malerba, and Philippe Pareige
- Atom probe analysis of ex-situ gas-charged stable hydrides
D. Haley, P.A.J. Bagot, and M.P. Moody
- Automated atom-by-atom 3D reconstruction of field ion microscopy data
Michael Moody, Michal Dagan, Baptiste Gault, George Smith, and Paul Bagot
- Modern FIB-Based Site-Specific Specimen Preparation for Atom Probe Tomography
Prosa, Ty and David Larson
- In-situ Atom Probe Deintercalation of Lithium-Manganese-Oxide
Björn Pfeiffer, Johannes Maier, Jonas Arlt, and Carsten Nowak
- True atomic-scale imaging in three-dimensions: A review of the rebirth of field-ion microscopy
Francois Vurpillot, Frédéric Danoix, Matthieu Gilbert, Sebastian Koelling, Michal Dagan, and David Seidman
- Detecting Clusters in Atom Probe Data with Gaussian Mixture Models
Jennifer Zelenty, Andrew Dahl, Jonathan Hyde, George Smith, and Michael Moody



Dear Abbe

Dear Abbe,

For the last few years I have been sentenced to research management, and I fear I am losing touch with the technical world. I am responsible for my group's execution of cutting-edge research. In industry terms, that involves generating pretty SEMs which please our upper management. Recently I have seen many color SEMs in online news items. I'm wondering: where can I purchase one of those nifty color electron microscopes? We all know about green M&Ms, but is there anything I should know about orange electrons?

De-lobed in Cincinnati

Dear Lobeless,

It would seem that you and your upper management have been hoodwinked by one of the oldest tricks in the book, namely falsely adding color to a black-and-white image. This practice was perfected by my dear friend Wallace Nutting who used the technique to peddle his photographs. At one time Wallace employed over 200 colorists who added just the right shades of green, pink, and brown to make it seem as if his photos were in color. Tricks, tricks, tricks! Secretly I think that he did this to get back at those who had chopped the head off of his great-grandfather and stuck in on a pike, but Wallace assured me that it was done solely to amass wealth. These days Rechtsverdreher Microscope sellers have found that gullible labs will still fall for this subterfuge. As P.T. Barnum once noted, "A fool and his money will make my wallet fat!" Next time your boss wants a colorized SEM, do what I do. Distribute a stack of photos to a bunch of third graders and ask them to use crayons to make the pictures "pretty." Choose the best one and tell your boss that it cost \$1,500. Buy the kid an ice cream and pocket the difference.

If you feel threatened by the colorful world around you, put your dark shades on and consult Herr Abbe. He can be reached by contacting his faithful assistant at jpshield@uga.edu.

MT